TOSHIBA Photocoupler GaAlAs Ired & Photo IC

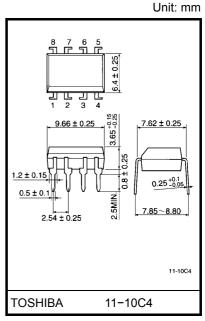
6N135, 6N136

Digital Logic Isolation
Line Receiver
Power Supply Control
Switching Power Supply
Transistor Inverter

The TOSHIBA 6N135 and 6N136 consists of a high emitting diode and a one chip photo diode–transistor.

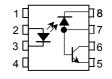
Each unit is 8-lead DIP package.

- Isolation voltage: 2500 V_{rms} (min)
- High speed: t_{pHL} , $t_{pLH} = 0.5 \mu s$ (typ.) ($R_L = 1.9 k\Omega$)
- TTL compatible
- If base pin is open, output signal will be noisy by environmental condition. For this base, TLP550 is suitable
- UL recognized: UL1577, file no. E67349

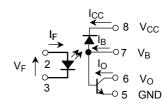


Weight: 0.54 g (typ.)

Pin Configurations



- 1 : N.C.
- 2 : ANODE
- 3: CATHODE
- 4 : N.C
- 5: EMITTER
- 6: COLLECTOR
- 7: BASE, ANODE
- 8 : CATHODE



Absolute Maximum Ratings (Ta = 25°C)

Characteristic			Symbol	Rating	Unit
LED	Forward current	(Note 1)	l _F	25	mA
	Pulse forward current	(Note 2)	I _{FP}	50	mA
	Total pulse forward current	(Note 3)	I _{FPT}	1	Α
	Reverse voltage		V_{R}	5	V
	Diode power dissipation	(Note 4)	P_{D}	45	mW
	Output current		Io	8	mA
Detector	Peak output current		I _{OP}	16	mA
	Emitter-base reverse voltage (p	V _{EB}	5	V	
	Supply voltage		V _{CC}	-0.5 to 15	V
	Output voltage		VO	-0.5 to 15	V
	Base current (pin 7)		ΙΒ	5	mA
	Output power dissipation	(Note 5)	Po	100	mW
Opera	Operating temperature range		T _{opr}	-55 to 100	°C
Storage temperature range			T _{stg}	-55 to 125	°C
Lead	Lead solder temperature (10s) (Note 6)		T _{sol}	260	°C
Isolati	Isolation voltage (Note 7)		BVS	2500	V _{rms}

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

- (Note 1) Derate 0.8 mA above 70°C.
- (Note 2) 50% duty cycle, 1ms pulse width. Derate 1.6 mA / °C above 70°C.
- (Note 3) Pulse width 1µs, 300pps.
- (Note 4) Derate 0.9 mW / °C above 70°C.
- (Note 5) Derate 2 mW / °C above 70°C.
- (Note 6) Soldering portion of lead: Up to 2mm from the body of the device.
- (Note 7) R.H. ≤ 60%, AC, 1minute

Electrical Characteristics Over Recommended Temperature (Ta = 0°C~70°C unless otherwise noted)

Characteristic		Symbol	Test Condition	Min	(**)Typ.	Max	Unit
	6N135	CTR	I _F = 16mA, V _O = 0.4V	7	18	_	%
Current transfer ratio	6N136	CIR	$V_{CC} = 4.5V$, $Ta = 25^{\circ}C$ (Note 8)	19	24	_	%
Current transfer fallo	6N135	CTR	I _F = 16mA, V _O = 0.5V	5	13	_	%
	6N136	CIR	$V_{CC} = 4.5V$ (Note 1)	15	21	_	%
Logic low output voltage	6N135	V _{OL}	I _F = 16mA, I _O = 1.1mA V _{CC} = 4.5V	_	0.1	0.4	٧
Logic low output voltage	6N136	VOL	I _F = 16mA, I _O = 2.4mA V _{CC} = 4.5V	_	0.1	0.4	٧
Logic high output current		Іон	$I_F = 0$ mA, $V_O = V_{CC} = 5.5$ V Ta = 25°C	_	3	500	nA
			I _F = 0mA, V _O = V _{CC} = 15V Ta = 25°C	_	0.1	1	μА
		loh	I _F = 0 mA, V _O = V _{CC} = 15V	_	_	50	μА
Logic low supply current		ICCL	I _F = 16mA, V _O = open V _{CC} = 15V	_	40	_	μА
Logic high supply current		Іссн	I_F = 0mA, V_O = open V_{CC} = 15V, Ta = 25°C	_	0.01	1	μΑ
		Іссн	$I_F = 0mA$, $V_O = open$ $V_{CC} = 15V$	_	_	2	μА
Input forward voltage		V _F	I _F = 16mA, Ta = 25°C	_	1.65	1.7	V
Temperature coefficient of forward voltage		ΔV _F / ΔTa	I _F = 16mA	_	-1.9	_	mV / °C
Input reverse breakdown voltage		BV _R	I _R = 10μA, Ta = 25°C	5	_		V
Input capacitance		C _{IN}	f = 1MHz, V _F = 0	_	60	_	pF
Resistance (input-output)		R _{I-O}	V _{I-O} = 500V (Note 9) R.H. ≤ 60%	_	10 ¹²	_	Ω
Capacitance (input-output)		C _{I-O}	f = 1MHz (Note 9)	_	0.6	_	pF
Transistor DC current gain		h _{FE}	V _O = 5V, I _O = 3mA	_	80	_	_

^(**) All typical values are at Ta = 25° C

Switching Specifications (unless otherwise specified. Ta = 25° C, V_{CC} = 5V, I_{F} = 16mA)

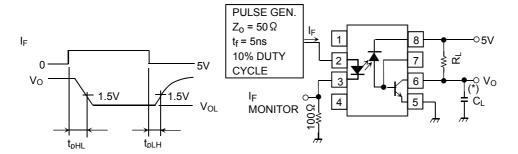
Characteristic		Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Propagation delay time	6N135	- t _{pHL}	1	$R_L = 4.1k\Omega$	_	0.2	1.5	μs
to logic low at output	6N136			R _L = 1.9kΩ	_	0.2	0.8	μs
Propagation delay time	6N135	t _{pLH}	1	$R_L = 4.1k\Omega$	_	1.0	1.5	μs
to logic high at output	6N136			$R_L = 1.9k\Omega$	1	0.5	0.8	μs
Common mode transient immunity	6N135	- CM _H	2	$I_F = 0\text{mA}$ $V_{CM} = 10V_{p-p}$ $R_L = 4.1\text{k}\Omega$	ı	1000	ı	V / µs
at logic high level output (Note 10)	6N136			$I_F = 0\text{mA}$ $V_{CM} = 10V_{p-p}$ $R_L = 1.9k\Omega$	-	1000	-	V / μs
Common mode transient immunity	6N135	CMI	2	$V_{CM} = 10V_{p-p}$ $R_L = 4.1k\Omega$ $I_F = 16mA$	ı	-1000	ı	V / μs
at logic low level output (Note 10)	6N136	OWL	2	$V_{CM} = 10V_{p-p}$ $R_L = 1.9k\Omega$ $I_F = 16mA$		-1000		V / μs
Bandwidth (Note 11)		BW	_	R _L = 100Ω	_	2	_	MHz

- (Note 8) DC current transfer ratio is defined as the ratio of output collector current, I_O , to the forward LED input current, I_F , times 100%.
- (Note 9) Device considered a two-terminal device: Pins 1, 2, 3 and 4 shorted together and pins 5, 6, 7 and 8 shorted together.
- (Note 10) Common mode transient immunity in logic high level is the maximum tolerable (positive) dV_{CM} / dt on the leading edge of the common mode pulse, V_{CM}, to assure that the output will remain in a logic high state (i.e., V_O > 2.0V).
 Common mode transient immunity in logic level logic level is the maximum tolerable (positive) dV_{CM} / dt on the

Common mode transient immunity in logic low level is the maximum tolerable (negative) dV_{CM} / dt on the trailing edge of the common mode pulse signal, V_{CM} , to assure that the output will remain in a logic low state (i.e., $V_O < 0.8V$).

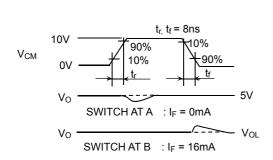
(Note 11) The frequency at which the AC output voltage is 3dB below the low frequency asymptote.

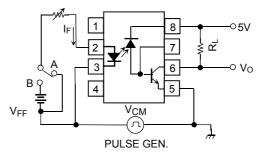
Test Circuit 1.



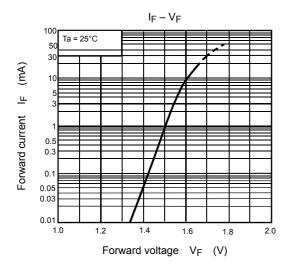
(*) C_L is approximately 15_PF which includes probe and stray wiring capacitance.

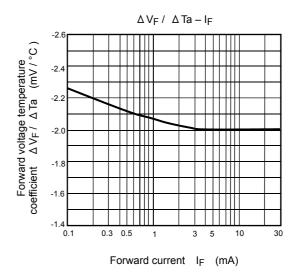
Test Circuit 2.

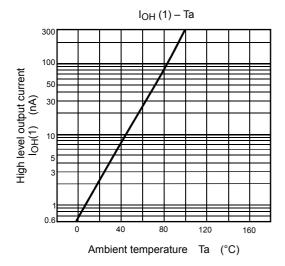


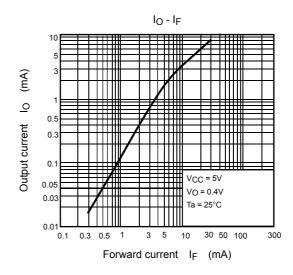


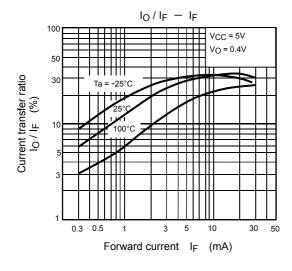
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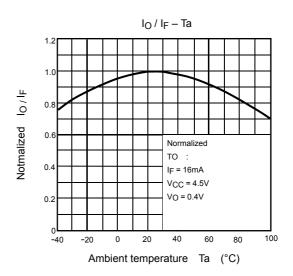


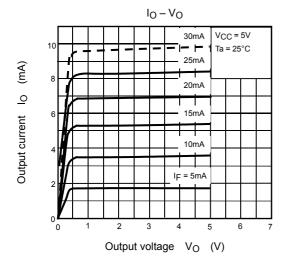


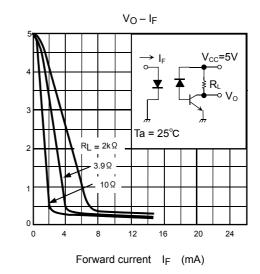






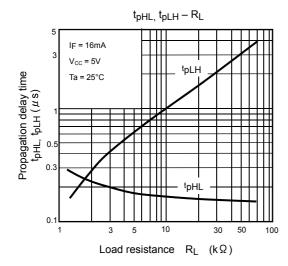






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Output voltage Vo



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